

## 55GHz Octal-site Wafer Test Probecard for 5G mmWave devices

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# Intro: 5G mmWave Drivers

#### Demand

- Urban area capacity, fixed wireless broadband (FWA), video streaming, AR/VR, Critical IOT such as autonomous vehicles and mobile healthcare
- Frequency
  - 5G FR2 (frequency range 2) (24.25GHz to 52.6GHz)
  - Bandwidth up to 3.4GHz

- 5G Comparison:
  - 5G sub-6Ghz 200Mb/s
  - 5G mmWave 5Gb/s

5G **7** 5G

https://www.macrumors.com/quide/mmwave-vs-sub-6ghz-5g/

- Percentage mmWave sales
  - 43% phones by 2022







# **Introduction – RF Probing Challenges**

### General probing challenges

- Planarity
- Overdrive
- Maintenance
- Initial Cost
- COT
- Throughput
- Yield
- Routing
- Temperature

### RF probe card challenges

- Higher Initial Cost
- Exotic Space transformers
- Multisite limitations
- Loss
- Reflections
- Repeatability
- Tester resource Limitations
- Components, connectors, switching, cabling

# **WLCSP Objectives / Goals**

### Mechanical targets

- 600+ i/o die
- 150um pitch
- Octal Site Probecard
- ~5000 contacts
- <50um planarity</p>
- >100 RF connectors/cables
- >100 01005 components (capacitors, resistors)
- >80 RF mmWave switches
- Full probecard including stiffener, cabling, docking, RF brackets, etc.

### Electrical targets

- 55GHz to tester
- 55Ghz loopback
- 44GHz switching
- Low impedance power supplies
- -10dB max return loss
- 50ohm impedance match
- Simulated and measured full path from tester to DUT for calibration and de-embedding

# **Methods/Materials**

#### **cRacer** Probehead

- 3mm test height spring probe, 150um pitch, 6g, 150um overdrive (DUT side)
- Metal frame, stiffener, 8 site MA
- Simulated and optimized signal integrity, bowing/stress analysis
- Measured life cycle, cRes, CCC, RF, planarity, force

#### **Direct Attach PCB**

- Fanout in PCB (no space transformer/MLO/MLC required)
- 100+ RF channels (5GHz-55GHz RF paths)
  - Simulated signal integrity (HFSS, SI Wave)
  - DUT side: surface, internal
  - Tester side: surface, internal
- 25 Power supplies
  - Simulated IR drop and impedance (SI Wave) all 8 sites

#### **Connectors/Cabling**

- SMPM connectors, Cabling
  - Simulated launch geometries

#### Switching

- 44GHz dual pole switches
- Simulated launch geometries

#### Components

- 01005 capacitors and resistors for signal integrity and space savings
- Simulated footprints

#### Simulation and **Measurement equipment**

- Ansys CFD, HFSS, SI Wave
- PCA (Cohu FReD machine)
- VNA (67GHz Keysight)
- Cycler (Kita)





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## **cRacer Optimization Process (Patent Pending)**

- Select pin based on required pitch and tip profile (150um crown tip in this case)
- Select contactor materials for PRP, Spacer, Body and FAP to provide required mechanical strength and dielectric performance
- Simulate RF performance in GSG or GSSG configuration
- Tune performance by matching to required impedance (typically 50 Ohms) across bandwidth of interest



PRP = Probe Retainer Plate FAP = Floating Alignment Plate

## **Radial Probe cRes Optimization**

- Expertise leveraged for performance
- **Back to the Basics** 
  - Low and consistent cRes
  - Lot-to-lot stability
  - Long lifetime
  - Optimized "Guts"

and cross sections



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## **Bowing Simulation – Rev 04**

- Predict the bowing deflection due to probe preload that can be expected from Probehead using Ansys simulation
- Max Y-Directional Deformation: 10.3 μm



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## **cRacer Probehead Simulated Insertion Loss**

 Predict the insertion loss and return loss expected from Probehead using Ansys simulation out to 55GHz

Great performance with <1dB Insertion loss, <-12dB return loss through 60GHz</li>





## **cRacer 150 Return loss Correlation**

#### cRacer150 GSG Probehead RF Measurement to RF Simulation correlation

- Great correlation between simulation and measurement
- simulation -12dB, measurement -10dB @ 53GHz



## **RL issue for mmWave signals**

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- High return loss found for mmWave signals on device
- Alternative materials attempted
- Impedance is still too low (approx. 40Ω)
  - Recommended Solution > De-Populate the 3<sup>rd</sup> GND Probe in the Probehead
  - Return loss before -7dB, Return loss after -12dB



## **mmWave Simulation: cRacer with PCB Launch**



## **DC Simulations (1V supply)**

Target IR drop less than 24mV (16mV Max simulated) achieved thru Ansys SI Wave simulation

**Voltage Drop** 

Current Density



# **Power Supply Impedance modeling**

- Site 1, 2 power supply configuration
- Impedance improvement after Decoupling







# **LO Full Path Simulation example**

#### Simulation Includes:

- DUT pad (HFSS), CPW trace (W-element), connector(HFSS), coaxial cable(2D) , bias-T (s-param) , switch (s-param), bypass caps (s-param), LNA (HFSS, sparam), divider (HFSS, s-param)
- Used for de-embedding in test program prior to full path s-parameter measurements



#### Schematic





## **Full Path S-parameter measurment to 55GHz**

- Tester to DUT full path loss (qty12 55GHz paths)
  - Return loss below -10dB and linear insertion loss thru 55GHz
  - Includes contactor, vias, traces, connector, 18" coax cable







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## **Probehead Inspection**

- Resistance Average: 250mOhm
- Resistance STD: 30mOhm
- Force Average: 4g
- Force STD: 0.2g

Cohu Probe H









/ Cohu



- First touch average: 3.36mm
- First touch STD: 7um
- Min tip height: 3.335
- Max tip height: 3.374
- Coplanarity: 41um

**Probe Head Inspection Report** 



**Probe Head Inspection Report** 



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### cRacer 55GHz Octal-Site Direct Attach Probe Card











# **Discussion of Results**

#### Advantages

- 8+ site capable mmWave Probecard Solution
- Traditional Spring Probe Technology
- Direct Attach (no MLO/MLC)
- Field maintainable
- Lower Cost of Test

### Challenges

- Significant Engineering Design effort
- Limited real-estate limits optimal RF Routing
- Complex PCB stackup
- High BOM count/cost and assembly complexity
- Long-leadtime mmWave components



# **Summary / Conclusion**

- Proven performance and parallelism of a cRacer probehead+Direct attach PCB for up to mmWave and down to 150um pitch
  - Turnkey Production Probe solution for any RF application from DC to Daylight
- Design, Simulation, Prototype and Final build efforts to deliver
  - Required mechanical and electrical expertise, supply chain management, assembly and test coordination, and logistics management to get the job done right the first time

# **Follow-On Work**

- Redesign for alternative impedance profile
- Optimize cable lengths and routing for lower loss
- Improve manual actuator for singulated die testing
- Simplify logistics for High Volume Deliveries



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